



## AO4600

### Complementary Enhancement Mode Field Effect Transistor

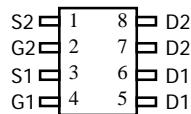
#### General Description

The AO4600 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge. The complementary MOSFETs form a high-speed power inverter, suitable for a multitude of applications.

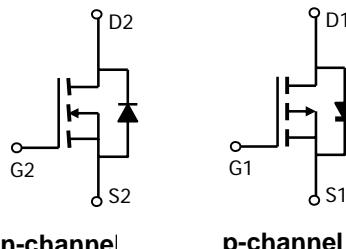
*Standard Product AO4600 is Pb-free (meets ROHS & Sony 259 specifications). AO4600L is a Green Product ordering option. AO4600 and AO4600L are electrically identical.*

#### Features

n-channel	p-channel
$V_{DS}$ (V) = 30V	-30V
$I_D$ = 6.9A ( $V_{GS}$ = 10V)	-5A ( $V_{GS}$ = -10V)
$R_{DS(ON)}$	
< 27mΩ	< 49mΩ ( $V_{GS}$ = -10V)
< 32mΩ	< 64mΩ ( $V_{GS}$ = -4.5V)
< 50mΩ	< 120mΩ ( $V_{GS}$ = -2.5V)



SOIC-8



#### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Max n-channel	Max p-channel	Units
Drain-Source Voltage	$V_{DS}$	30	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	$\pm 12$	V
Continuous Drain Current <sup>A</sup>	$I_D$	6.9	-5	A
$T_A=70^\circ\text{C}$		5.8	-4.2	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	40	-30	
Power Dissipation	$P_D$	2	2	W
$T_A=70^\circ\text{C}$		1.44	1.44	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	-55 to 150	°C

#### Thermal Characteristics: n-channel and p-channel

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	48	62.5	°C/W
Steady-State		74	110	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	35	40	°C/W

**n-channel MOSFET Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$		100		nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.7	1	1.4	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	25			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=6.9\text{A}$ $T_J=125^\circ\text{C}$	22.6	27		$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=6.0\text{A}$	33	40		$\text{m}\Omega$
		$V_{GS}=2.5\text{V}, I_D=5\text{A}$	27	32		$\text{m}\Omega$
			42	50		$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=5\text{A}$	12	16		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}$		0.71	1	V
$I_S$	Maximum Body-Diode Continuous Current				3	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		858	1050	pF
$C_{oss}$	Output Capacitance			110		pF
$C_{rss}$	Reverse Transfer Capacitance			80		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		1.24	4	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=15\text{V}, I_D=6.9\text{A}$		9.6	12	nC
$Q_{gs}$	Gate Source Charge			1.65		nC
$Q_{gd}$	Gate Drain Charge			3		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=2.2\Omega, R_{\text{GEN}}=6\Omega$		5.7		ns
$t_r$	Turn-On Rise Time			13		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			37		ns
$t_f$	Turn-Off Fall Time			4.2		ns
$t_{rr}$	Body Diode Reverse Recovery time	$I_F=5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		15.5	20	ns
$Q_{rr}$	Body Diode Reverse Recovery charge	$I_F=5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		7.9		nC

A: The value of  $R_{\text{JA}}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\text{JA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{JL}}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using 80  $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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## TYPICAL N-CHANNEL ELECTRICAL AND THERMAL CHARACTERISTICS

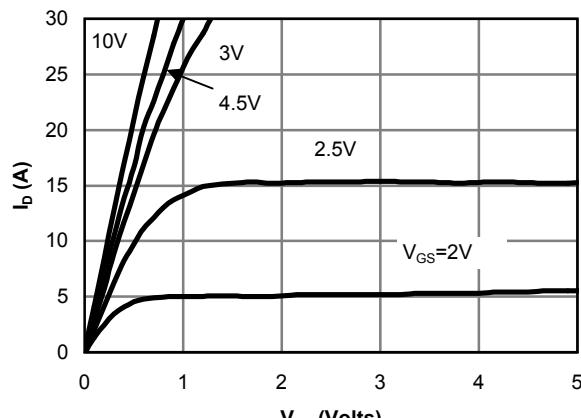


Fig 1: On-Region Characteristics

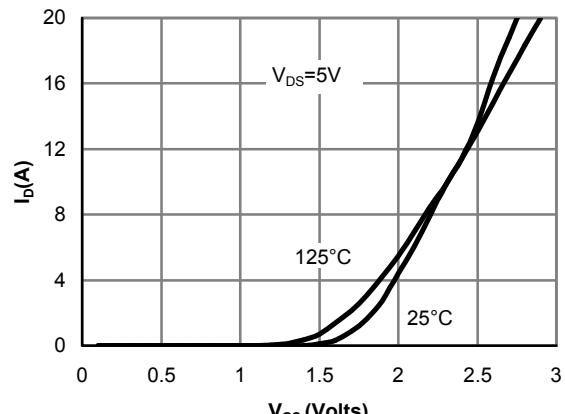


Figure 2: Transfer Characteristics

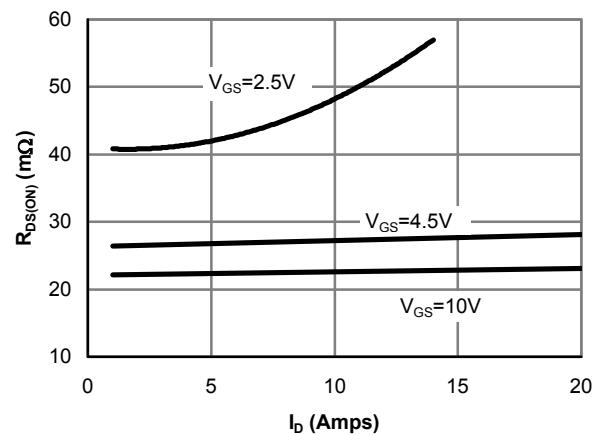


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

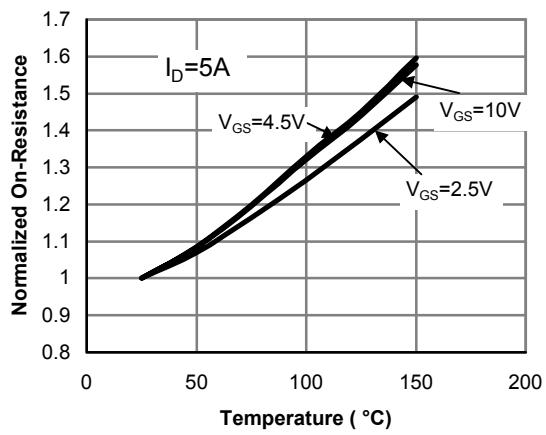


Figure 4: On-Resistance vs. Junction Temperature

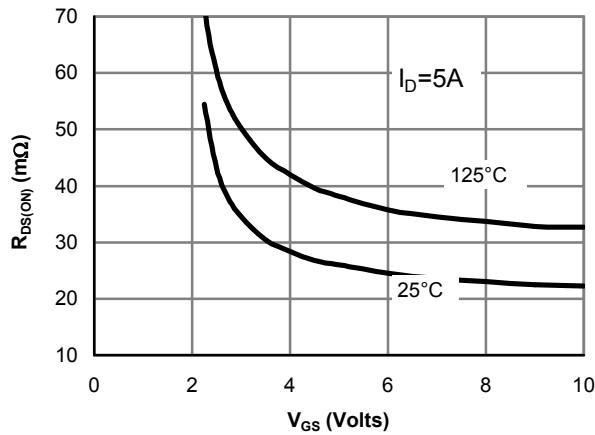


Figure 5: On-Resistance vs. Gate-Source Voltage

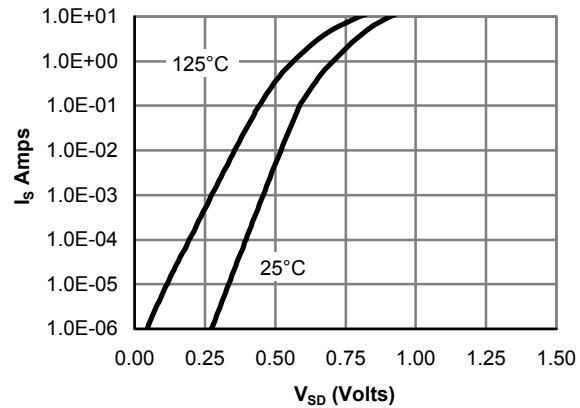


Figure 6: Body diode characteristics

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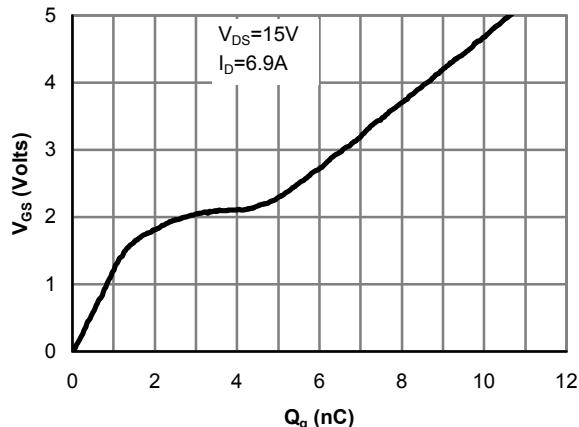


Figure 7: Gate-Charge characteristics

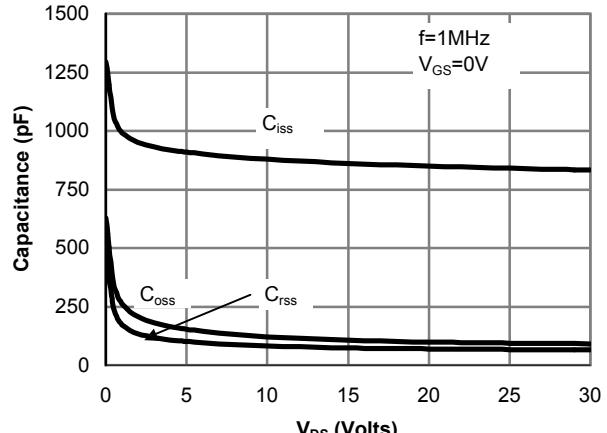


Figure 8: Capacitance Characteristics

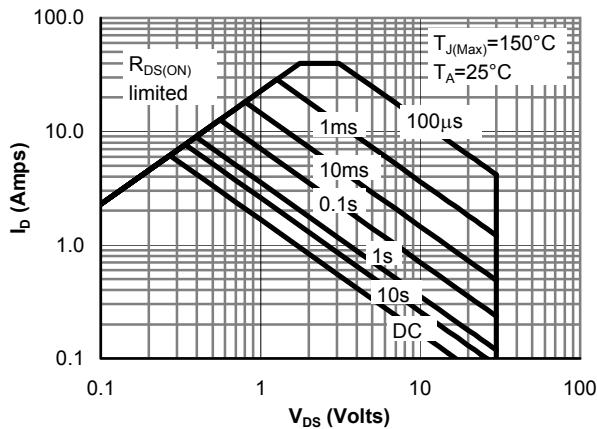


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

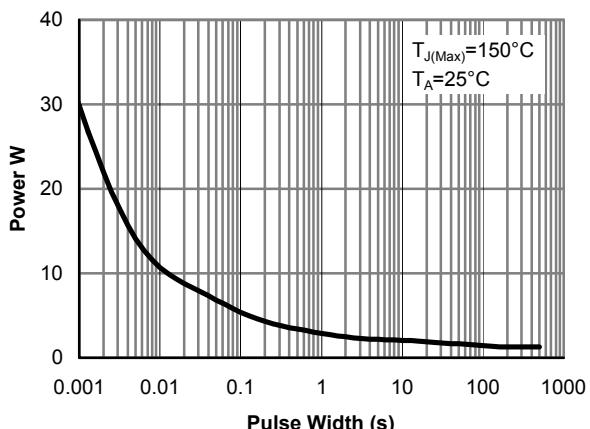


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

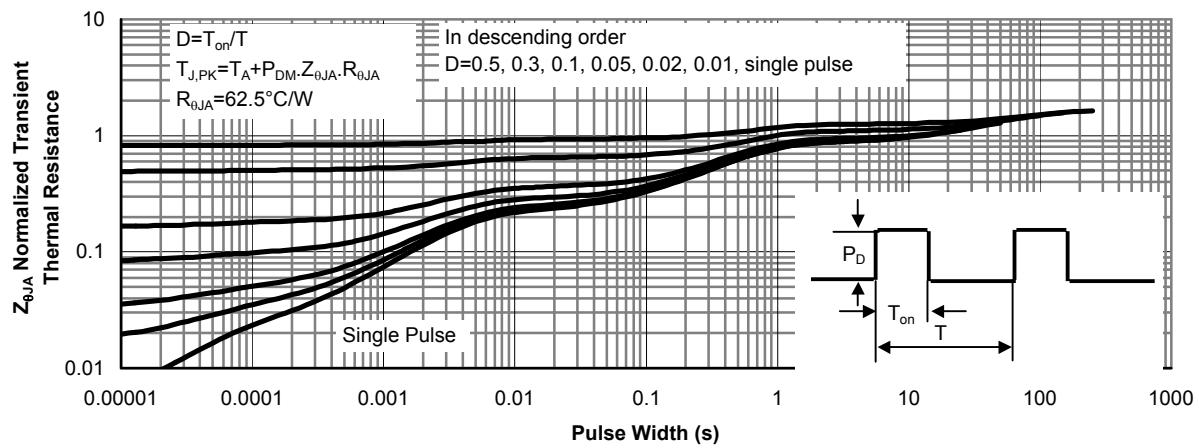


Figure 11: Normalized Maximum Transient Thermal Impedance

**p-channel MOSFET Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units	
<b>STATIC PARAMETERS</b>							
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V	
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-24\text{V}, V_{GS}=0\text{V}$	$T_J=55^\circ\text{C}$	-1	-5	$\mu\text{A}$	
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$			$\pm 100$	nA	
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.7	-1	-1.4	V	
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-25			A	
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-5\text{A}$		42.5	49	$\text{m}\Omega$	
		$T_J=125^\circ\text{C}$	74				
			54	64			
$R_g$	Gate resistance	$V_{GS}=-4.5\text{V}, I_D=-4\text{A}$		80	120	$\text{m}\Omega$	
		$V_{GS}=-2.5\text{V}, I_D=-1\text{A}$					
$g_{FS}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-5\text{A}$	7	11		S	
$V_{SD}$	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.75	-1	V	
$I_s$	Maximum Body-Diode Continuous Current				-3	A	
<b>DYNAMIC PARAMETERS</b>							
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		952	1200	pF	
$C_{oss}$	Output Capacitance			103		pF	
$C_{rss}$	Reverse Transfer Capacitance			77		pF	
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		5.9	30	$\Omega$	
<b>SWITCHING PARAMETERS</b>							
$Q_g$	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-15\text{V}, I_D=-5\text{A}$		9.5	12	nC	
$Q_{gs}$	Gate Source Charge			2		nC	
$Q_{gd}$	Gate Drain Charge			3.1		nC	
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=3\Omega, R_{\text{GEN}}=6\Omega$		12		ns	
$t_r$	Turn-On Rise Time			4		ns	
$t_{D(\text{off})}$	Turn-Off Delay Time			37		ns	
$t_f$	Turn-Off Fall Time			12		ns	
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=-5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		21	26	ns	
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=-5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		13		nC	

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D: The static characteristics in Figures 1 to 6, 12, 14 are obtained using 80 $\mu\text{s}$  pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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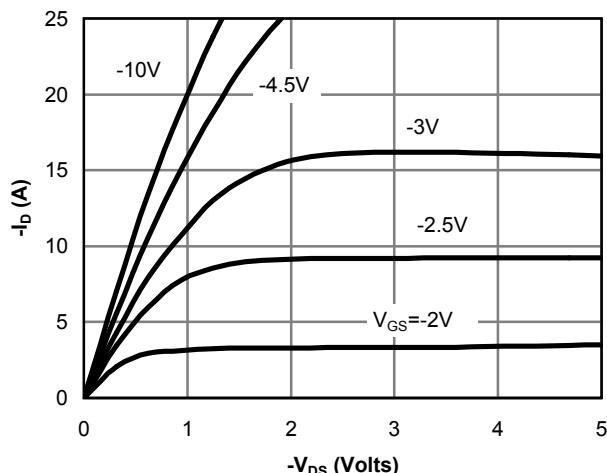


Fig 1: On-Region Characteristics

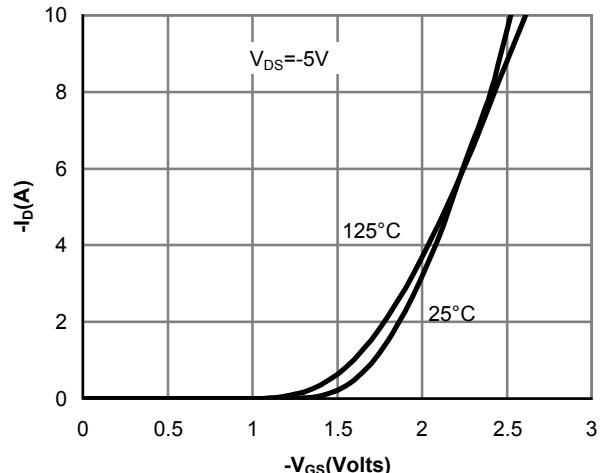


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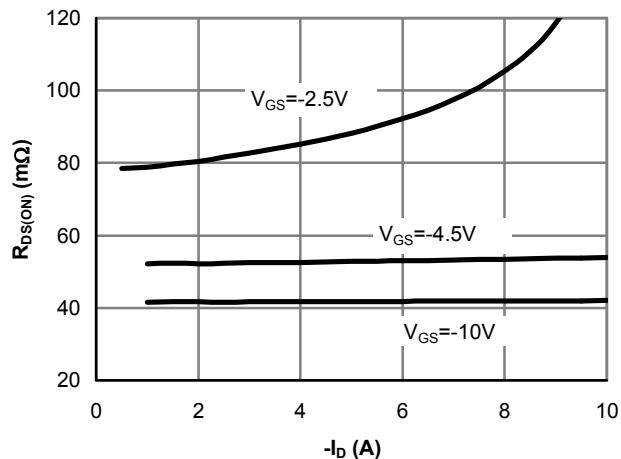


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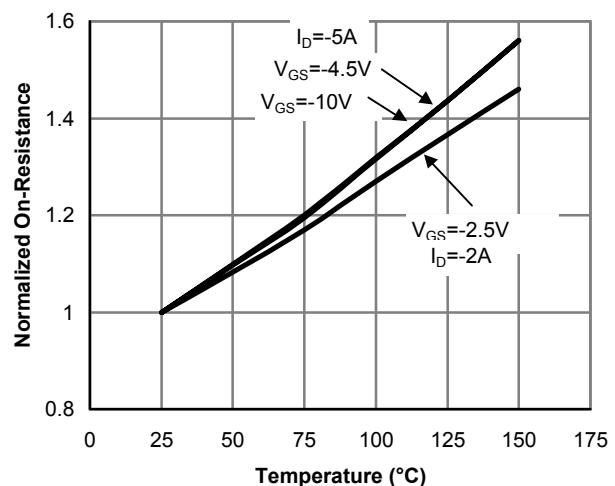


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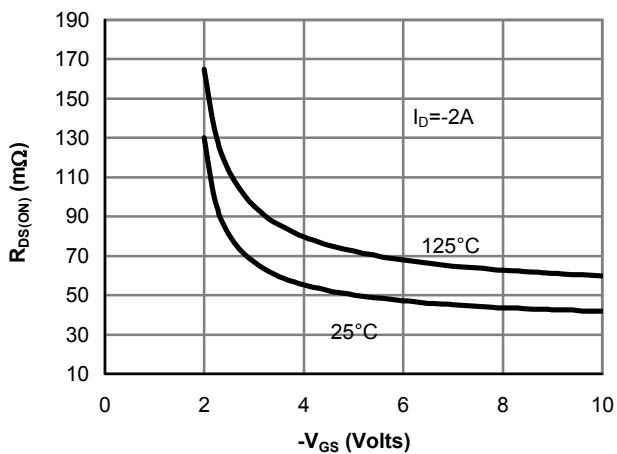


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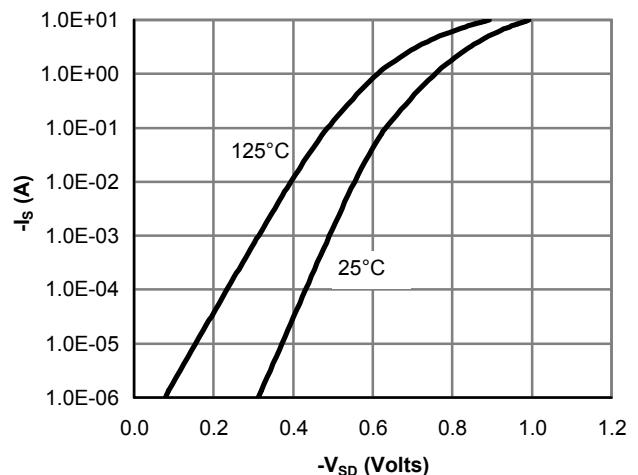


Figure 6: Body-Diode Characteristics

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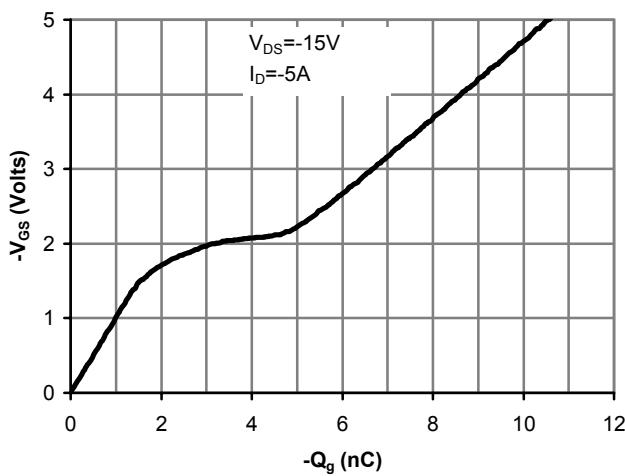


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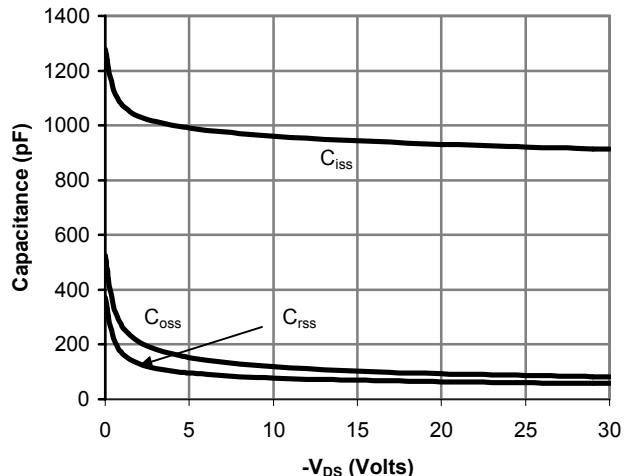


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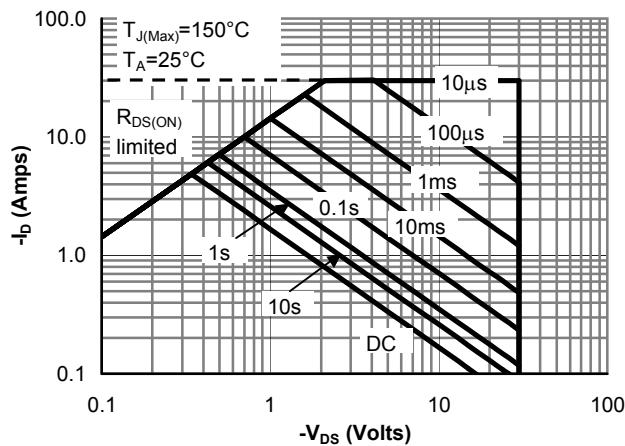


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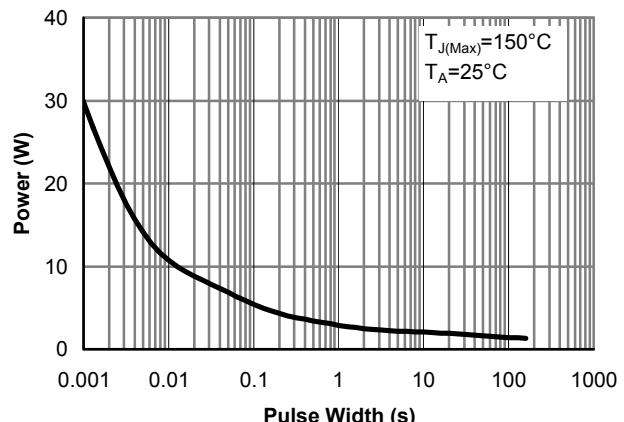


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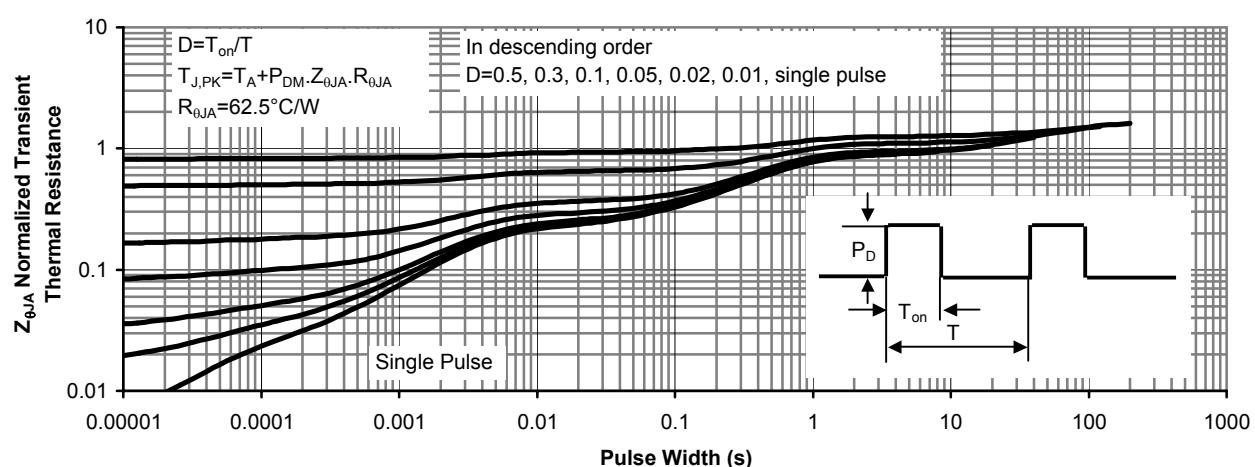


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